

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SHIN, CHEN-HWA	
		Examiner Tai Duong	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0055071	12-2001	Kawai et al.	348/333.06
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	L	US-			
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**NON-PATENT DOCUMENTS**

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